## Notice of References Cited Application/Control No. 09/809,181 Examiner José R Díaz Applicant(s)/Patent Under Reexamination SATOH ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,313,532 B1	11-2001	Shimoishizaka et al.	257/734
	В	US-6,452,270 B1	09-2002	Huang, Min-Lung	257/738
	С	US-2002/0130412 A1	09-2002	Nagai et al.	257/737
	D	US-6,111,317 A	08-2000	Okada et al.	257/737
	E	US-6,608,389 B1	08-2003	Hashimoto, Nobuaki	257/784
i	F	US-5,757,078	05-1998	Matsuda et al.	257/737
	G	US-5,773,888 A	06-1998	Hosomi et al.	257/737
	Н	US-6,624,504 B1	09-2003	Inoue et al.	257/668
	I	US-	7		
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
9 = 1	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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